

<b>Notice of References Cited</b>	Application/Control No. 09/532,398	Applicant(s)/Patent Under Reexamination BOERGER ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,486,945	11-2002	Haerle et al.	356/218
*	B	US-5,065,007	11-1991	Tanaka, Toshiaki	250/215
*	C	US-5,471,052	11-1995	Ryczek, Lawrence J.	250/226
*	D	US-6,087,846	07-2000	Alvord et al.	324/767
*	E	US-6,127,783	10-2000	Pashley et al.	315/149
*	F	US-6,180,415	01-2001	Schultz et al.	436/518
*	G	US-6,342,945	01-2002	Allen et al.	356/73.1
*	H	US-5,803,579	09-1998	Turnbull et al.	362/516
	I	US-6,130,700 A	10-2000	Murayama et al.	347/240
	J	US-5,894,341	04-1999	Nishi et al.	355/68
	K	US-5,589,741 A	12-1996	Terman et al.	315/360
	L	US-6,078,732 A	06-2000	Beretta, Giordano Bruno	358/1.9
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	PCT WO 01/27910 A1	04-2001	NL	Silvestre et al.	G09G 3/32
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Solid State Devices and Applications", F. Driscoll, pp. 370-380, Prentice-Hall Inc. 1975
	V	"Microelectronic Circuits", A. S. Sedra, Holt, Rinehart, and Winston Inc. pp. 193-194, 1987
	W	"The Investigation of CCD Cameras and Image Processing Techniques for the Large Adaptive Reflector CCD Camera Based surface Measurement System", B. Carlson, Image Processing for LAR surface Measurement, April 12, 1999
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.